

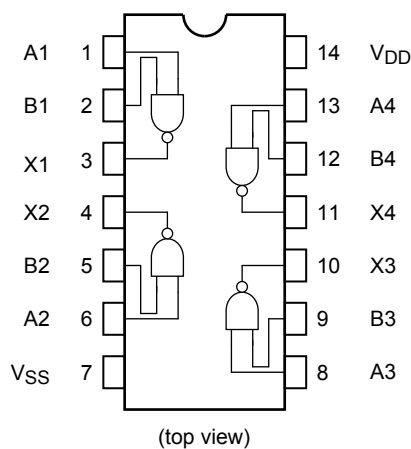
## TC4011BP, TC4011BF, TC4011BFN, TC4011BFT

### TC4011B Quad 2 Input NAND Gate

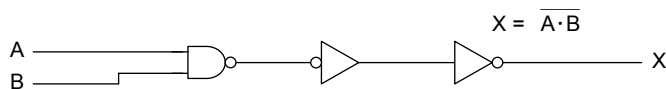
The TC4011B is 2-input positive logic NAND gate respectively.

Since all the outputs of these gates are provided with the inverters as buffers, the input/output characteristics have been improved and the variation of propagation delay time due to the increase in load capacity is kept down to the minimum.

### Pin Assignment

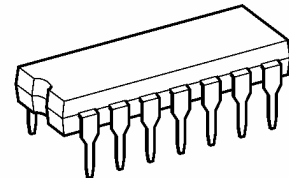


### Logic Diagram



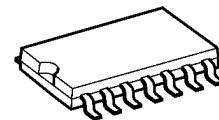
Note: xxxFN (JEDEC SOP) is not available in Japan.

TC4011BP



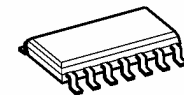
DIP14-P-300-2.54

TC4011BF



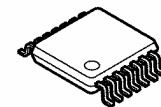
SOP14-P-300-1.27A

TC4011BFN



SOL14-P-150-1.27

TC4011BFT



TSSOP14-P-0044-0.65A

### Weight

DIP14-P-300-2.54	: 0.96 g (typ.)
SOP14-P-300-1.27A	: 0.18 g (typ.)
SOL14-P-150-1.27	: 0.12 g (typ.)
TSSOP14-P-0044-0.65A	: 0.06 g (typ.)

## Absolute Maximum Ratings (Note)

Characteristics	Symbol	Rating	Unit
DC supply voltage	$V_{DD}$	$V_{SS} - 0.5$ to $V_{SS} + 20$	V
Input voltage	$V_{IN}$	$V_{SS} - 0.5$ to $V_{DD} + 0.5$	V
Output voltage	$V_{OUT}$	$V_{SS} - 0.5$ to $V_{DD} + 0.5$	V
DC input current	$I_{IN}$	$\pm 10$	mA
Power dissipation	$P_D$	300 (DIP)/180 (SOIC)	mW
Operating temperature range	$T_{opr}$	-40 to 85	°C
Storage temperature range	$T_{stg}$	-65 to 150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

## Operating Ranges ( $V_{SS} = 0$ V) (Note)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
DC supply voltage	$V_{DD}$	—	3	—	18	V
Input voltage	$V_{IN}$	—	0	—	$V_{DD}$	V

Note: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either  $V_{DD}$  or  $V_{SS}$ .

**Static Electrical Characteristics ( $V_{SS} = 0$  V)**

Characteristics		Symbol	Test Condition	$V_{DD}$ (V)	-40°C		25°C			85°C		Unit
					Min	Max	Min	Typ.	Max	Min	Max	
High-level output voltage		$V_{OH}$	$ I_{OUT}  < 1 \mu A$ $V_{IN} = V_{SS}, V_{DD}$	5	4.95	—	4.95	5.00	—	4.95	—	V
				10	9.95	—	9.95	10.00	—	9.95	—	
				15	14.95	—	14.95	15.00	—	14.95	—	
Low-level output voltage		$V_{OL}$	$ I_{OUT}  < 1 \mu A$ $V_{IN} = V_{SS}, V_{DD}$	5	—	0.05	—	0.00	0.05	—	0.05	V
				10	—	0.05	—	0.00	0.05	—	0.05	
				15	—	0.05	—	0.00	0.05	—	0.05	
Output high current		$I_{OH}$	$V_{OH} = 4.6$ V	5	-0.61	—	-0.51	-1.0	—	-0.42	—	mA
			$V_{OH} = 2.5$ V	5	-2.50	—	-2.10	-4.0	—	-1.70	—	
			$V_{OH} = 9.5$ V	10	-1.50	—	-1.30	-2.2	—	-1.10	—	
			$V_{OH} = 13.5$ V	15	-4.00	—	-3.40	-9.0	—	-2.80	—	
			$V_{IN} = V_{SS}, V_{DD}$									
Output low current		$I_{OL}$	$V_{OL} = 0.4$ V	5	0.61	—	0.51	1.2	—	0.42	—	mA
			$V_{OL} = 0.5$ V	10	1.50	—	1.30	3.2	—	1.10	—	
			$V_{OL} = 1.5$ V	15	4.00	—	3.40	12.0	—	2.80	—	
			$V_{IN} = V_{DD}$									
Input high voltage		$V_{IH}$	$V_{OUT} = 0.5$ V	5	3.5	—	3.5	2.75	—	3.5	—	V
			$V_{OUT} = 1.0$ V	10	7.0	—	7.0	5.50	—	7.0	—	
			$V_{OUT} = 1.5$ V	15	11.0	—	11.0	8.25	—	11.0	—	
			$ I_{OUT}  < 1 \mu A$									
Input low voltage		$V_{IL}$	$V_{OUT} = 4.5$ V	5	—	1.5	—	2.25	1.5	—	1.5	V
			$V_{OUT} = 9.0$ V	10	—	3.0	—	4.50	3.0	—	3.0	
			$V_{OUT} = 13.5$ V	15	—	4.0	—	6.75	4.0	—	4.0	
			$ I_{OUT}  < 1 \mu A$									
Input current	"H" level	$I_{IH}$	$V_{IH} = 18$ V	18	—	0.1	—	$10^{-5}$	0.1	—	1.0	$\mu A$
	"L" level	$I_{IL}$	$V_{IL} = 0$ V	18	—	-0.1	—	$-10^{-5}$	-0.1	—	-1.0	
Quiescent supply current		$I_{DD}$	$V_{IN} = V_{SS}, V_{DD}$ (Note)	5	—	0.25	—	0.001	0.25	—	7.5	$\mu A$
				10	—	0.50	—	0.001	0.50	—	15.0	
				15	—	1.00	—	0.002	1.00	—	30.0	

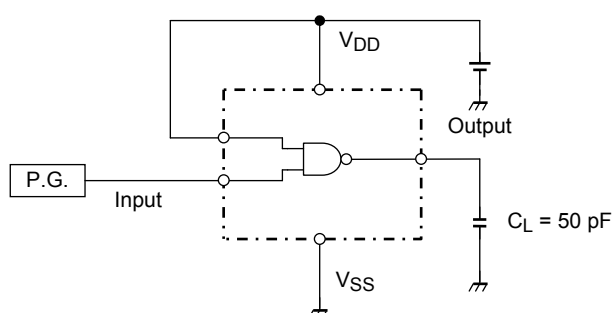
Note: All valid input combinations.

## Dynamic Electrical Characteristics (Ta = 25°C, VSS = 0 V, CL = 50 pF)

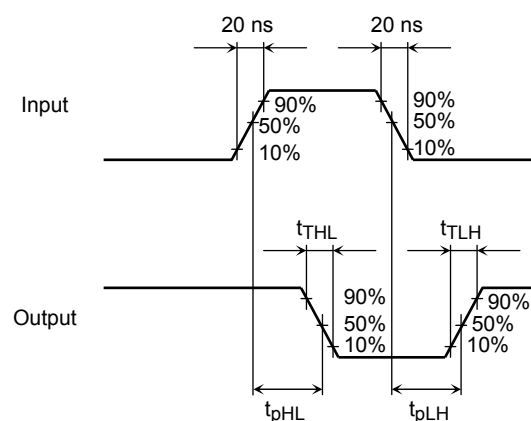
Characteristics	Symbol	Test Condition	VDD (V)	Min	Typ.	Max	Unit
Output transition time	$t_{TLH}$	—	5	—	70	200	ns
			10	—	35	100	
			15	—	30	80	
Output transition time	$t_{THL}$	—	5	—	70	200	ns
			10	—	35	100	
			15	—	30	80	
Propagation delay time	$t_{pLH}$	—	5	—	65	200	ns
			10	—	30	100	
			15	—	25	80	
Propagation delay time	$t_{pHL}$	—	5	—	65	200	ns
			10	—	30	100	
			15	—	25	80	
Input capacitance	$C_{IN}$	—	—	—	5	7.5	pF

## Circuit and Waveform for Measurement of Dynamic Characteristics

### Circuit



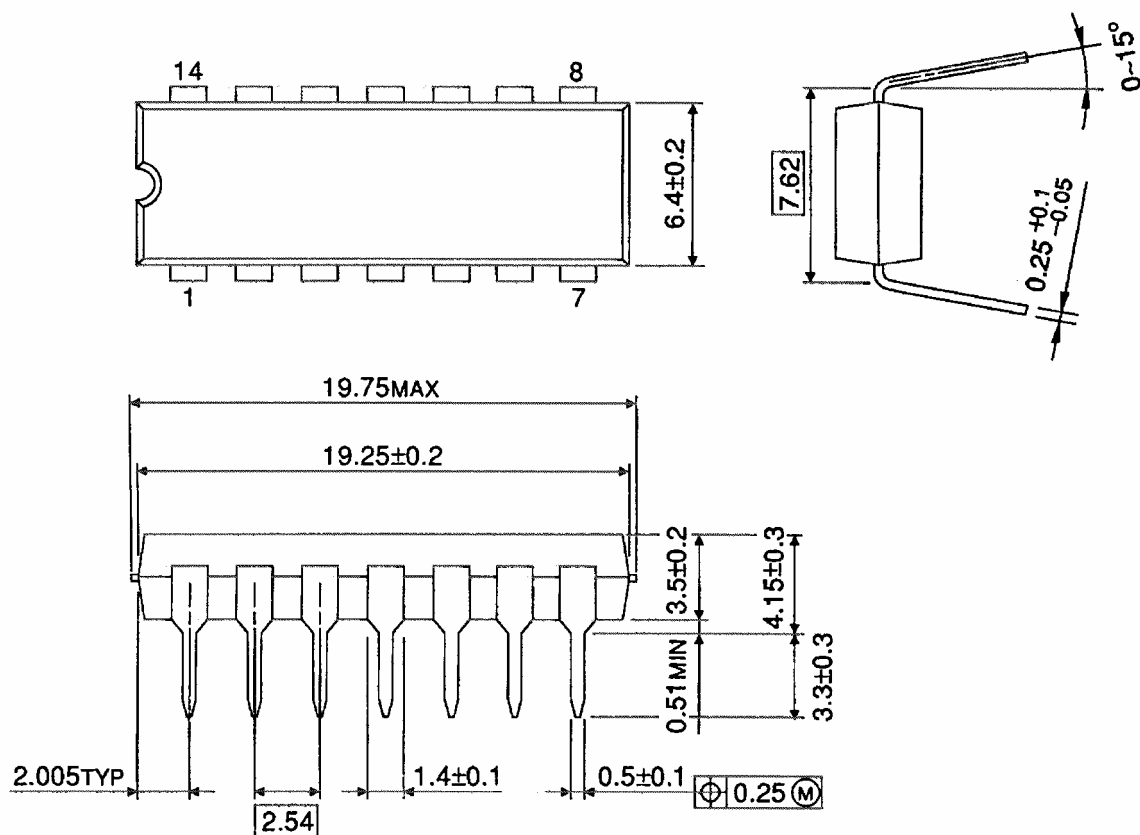
### Waveform



## Package Dimensions

DIP14-P-300-2.54

Unit : mm

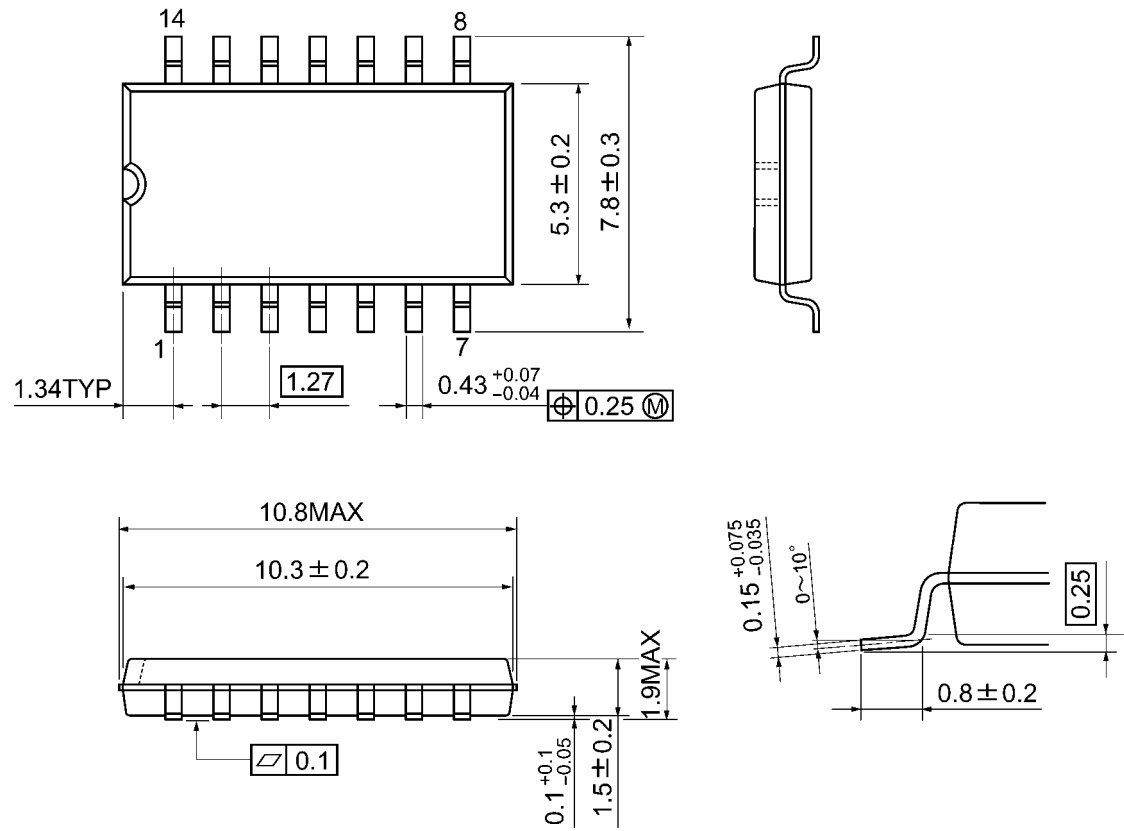


Weight: 0.96 g (typ.)

Package Dimensions

SOP14-P-300-1.27A

Unit: mm

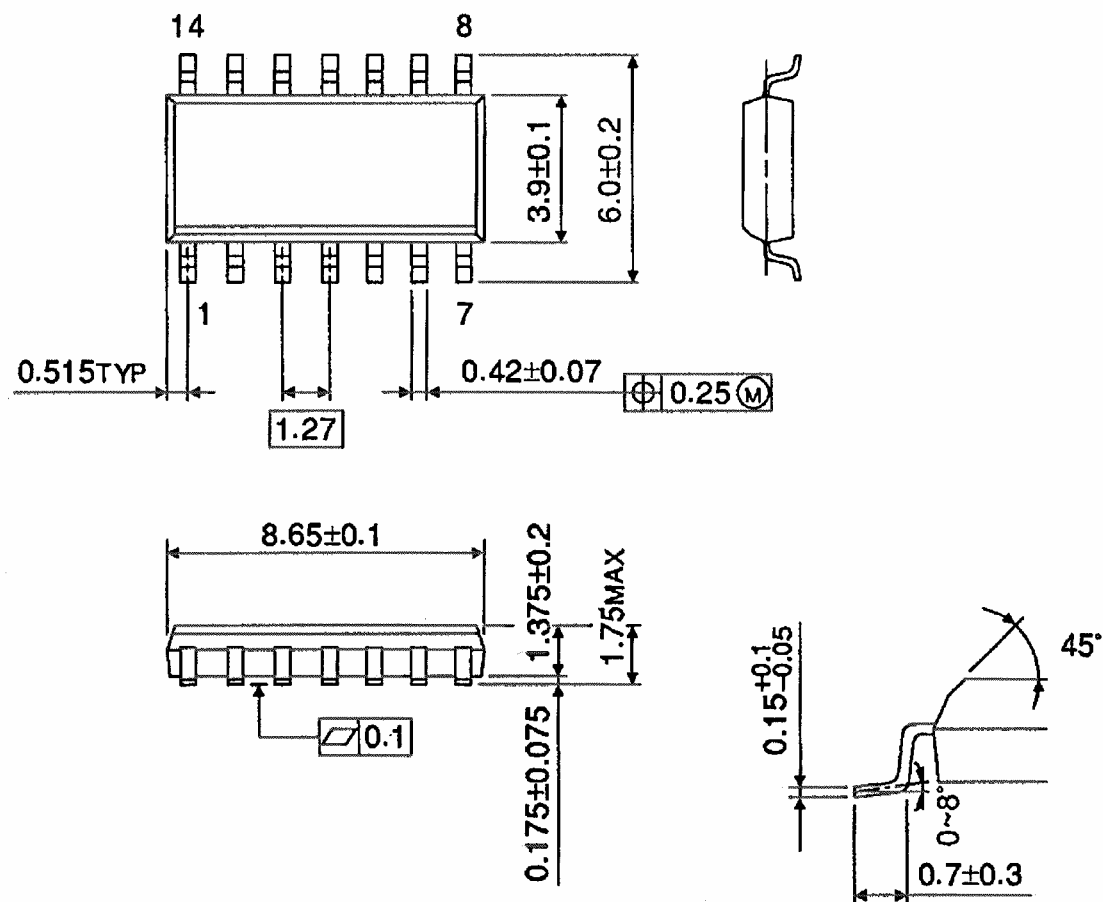


Weight: 0.18 g (typ.)

## Package Dimensions (Note)

SOL14-P-150-1.27

Unit : mm



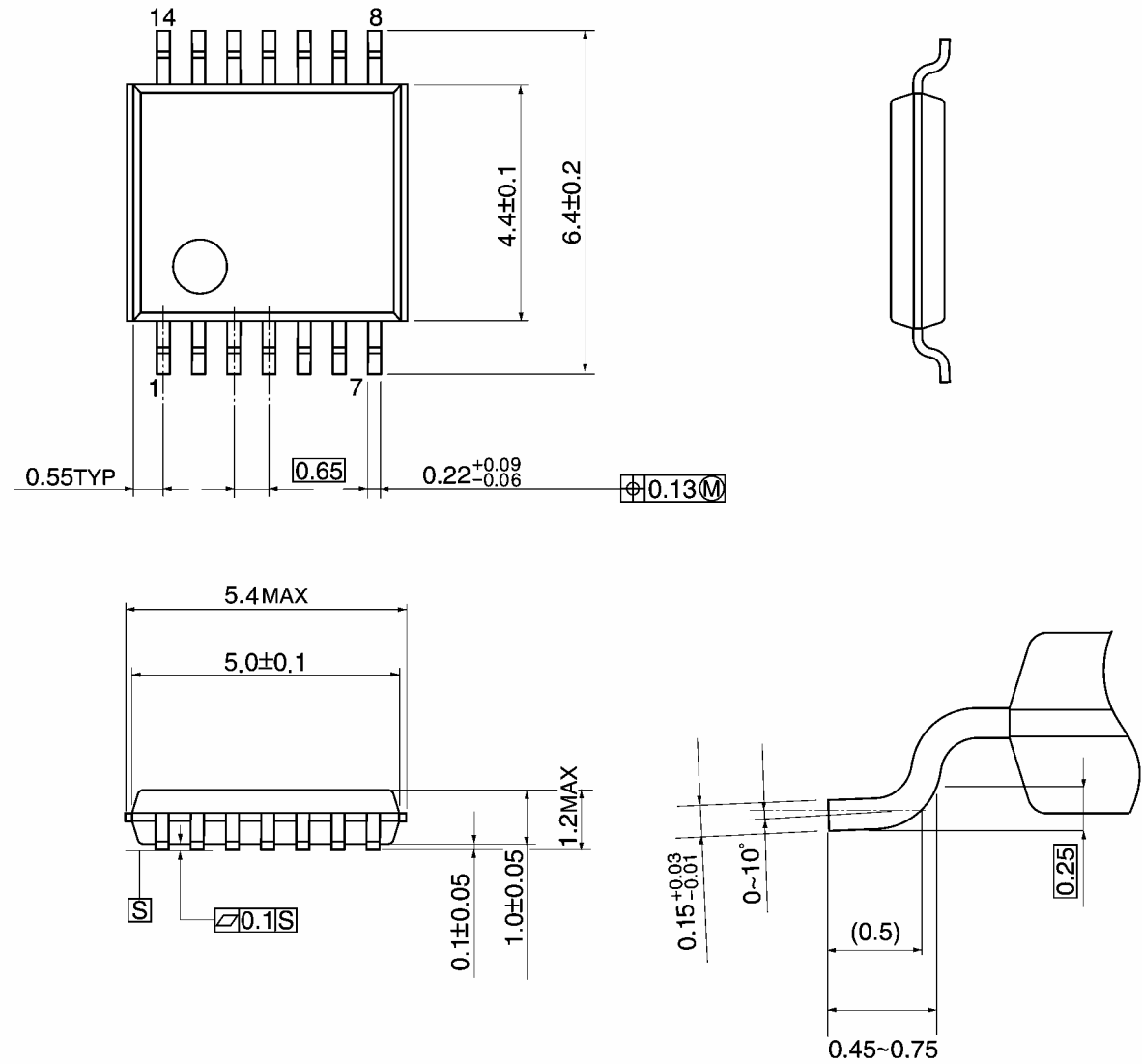
Note: This package is not available in Japan.

Weight: 0.12 g (typ.)

Package Dimensions

TSSOP14-P-0044-0.65A

Unit: mm



Weight: 0.06 g (typ.)



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20070701-EN GENERAL

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